



Features

- Split Gate Trench MOSFET technology
- Excellent package for heat dissipation
- High density cell design for low $R_{DS(ON)}$

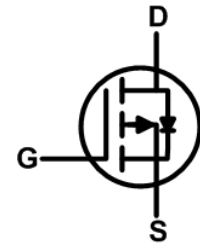
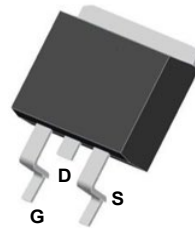
Product Summary

BVDSS	RDSON	ID
-60V	5.4 mΩ	-110A

Applications

- DC-DC Converters
- Power management functions
- Synchronous-rectification applications

TO263 Pin Configuration



Absolute Maximum Ratings ($T_C = 25^\circ\text{C}$ unless otherwise specified):

Symbol	Parameter	Value	Units
V_{DSS}	Drain-to-Source Voltage	-60	V
I_D	Continuous Drain Current	$T_C = 25^\circ\text{C}$	-110
	Continuous Drain Current	$T_C = 100^\circ\text{C}$	-70
I_{DM}^{a1}	Pulsed Drain Current	-440	A
V_{GS}	Gate-to-Source Voltage	± 20	V
P_D	Power Dissipation	180	W
E_{AS}^{a2}	Single pulse avalanche energy	960	mJ
T_J, T_{STG}	Operating Junction and Storage Temperature Range	150, -55 to 150	$^\circ\text{C}$
T_L	Maximum Temperature for Soldering	260	$^\circ\text{C}$

Thermal Characteristics:

Symbol	Parameter	Value	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.69	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	60	$^\circ\text{C}/\text{W}$

Electrical Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise specified):

Static Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
V_{DSS}	Drain to Source Breakdown Voltage	$V_{GS}=0V, I_D=-250\mu A$	-60	--	--	V
I_{DSS}	Drain to Source Leakage Current	$V_{DS} = -60V, V_{GS}= 0V$	--	--	1	μA
$I_{GSS(F)}$	Gate to Source Forward Leakage	$V_{GS} = -20V$	--	--	100	nA
$I_{GSS(R)}$	Gate to Source Reverse Leakage	$V_{GS} = +20V$	--	--	-100	nA
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu A$	-1.6	-2.0	-2.4	V
$R_{DS(ON)}$	Drain-to-Source On-Resistance	$V_{GS}=-10V, I_D=-15A$	--	5.4	7.0	$m\Omega$

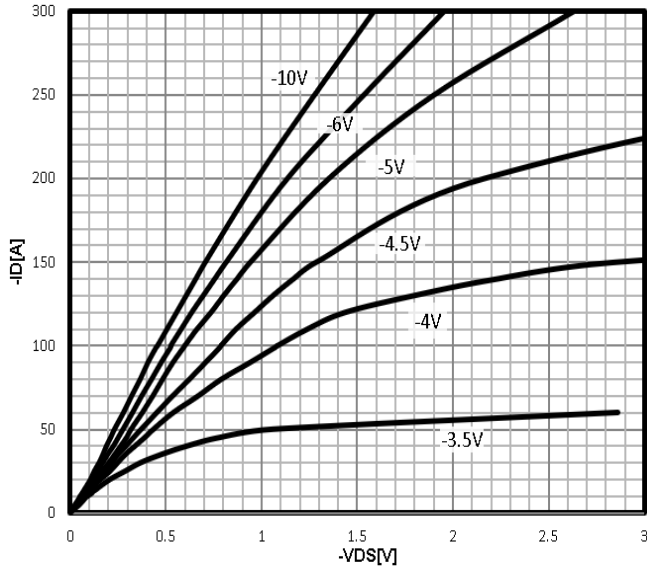
Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
C_{iss}	Input Capacitance	$V_{GS}=0V$ $V_{DS}=-30V$ $f=1.0MHz$	--	5403	--	pF
C_{oss}	Output Capacitance		--	941	--	
C_{rss}	Reverse Transfer Capacitance		--	48	--	
R_g	Gate resistance	$V_{GS}=0V, V_{DS}Open$	--	2.0	--	Ω

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time	$I_D=-15A, R_L=0.75\Omega$ $V_{DS}= -30V$ $V_{GS}= -10V$ $R_G= 3\Omega$	--	4.5	--	ns
t_r	Rise Time		--	2.5	--	
$t_{d(OFF)}$	Turn-Off Delay Time		--	14.5	--	
t_f	Fall Time		--	3.5	--	
Q_g	Total Gate Charge	$V_{GS}=-10V$ $V_{DS}=-30V$ $I_D=-15A$	--	80.2	--	nC
Q_{gs}	Gate Source Charge		--	15.2	--	
Q_{gd}	Gate Drain Charge		--	11	--	

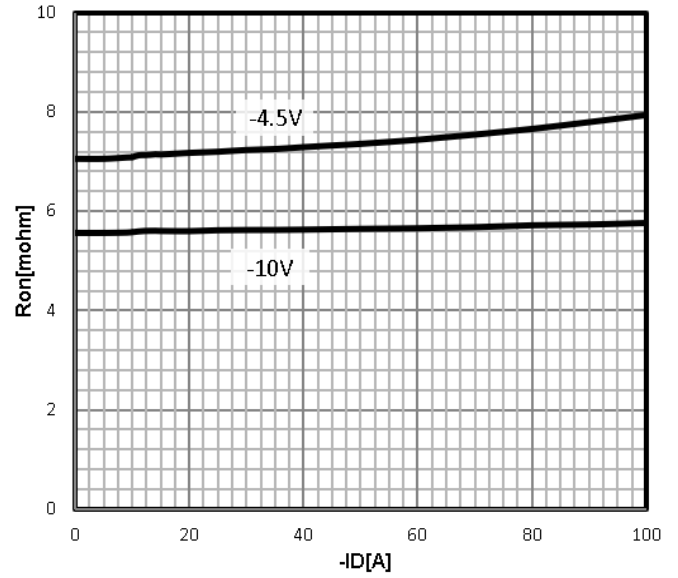
Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
I_S	Diode Forward Current	$T_C=25^\circ C$	--	--	-110	A
V_{SD}	Diode Forward Voltage	$I_S=-15A, V_{GS}=0V$	--	--	-1.2	V
t_{rr}	Reverse Recovery time	$I_S=-15A, V_{DD}=-30V$ $dI/dt=100A/\mu s$	--	60	--	ns
Q_{rr}	Reverse Recovery Charge		--	105	--	nC

Characteristics Curve:

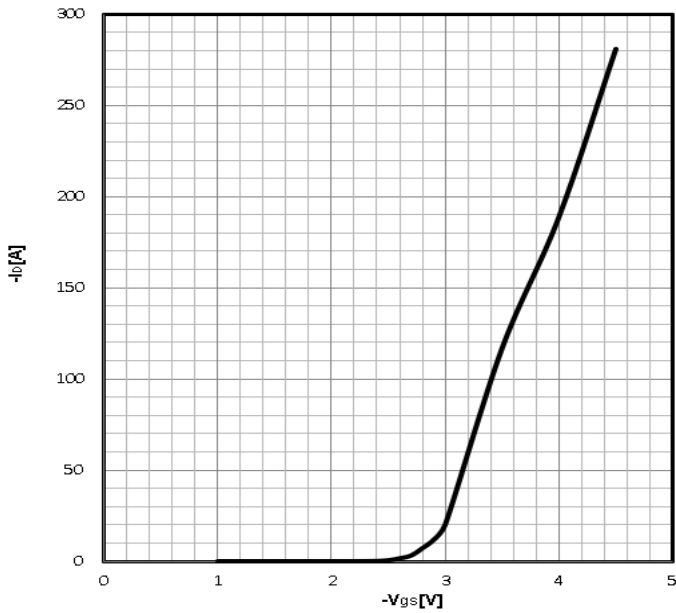
Typ. output characteristics
 $I_D=f(V_{DS})$



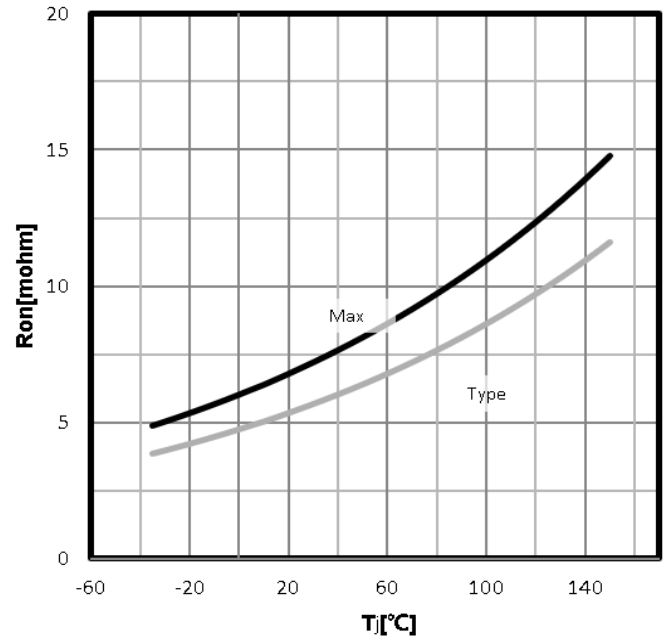
Typ. drain-source on resistance
 $R_{DS(on)}=f(I_D)$



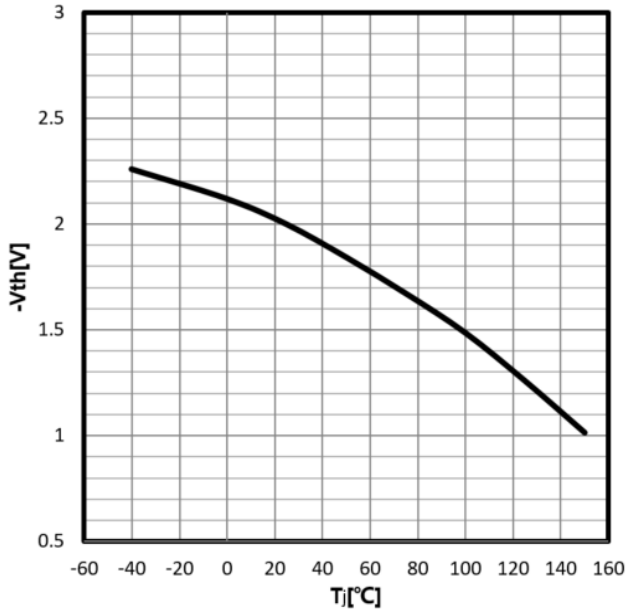
Typ. transfer characteristics
 $I_D=f(V_{GS})$



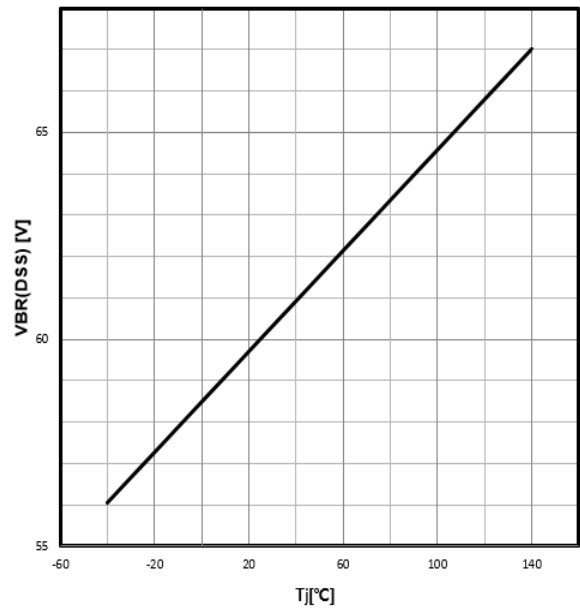
Drain-source on-state resistance
 $R_{DS(on)}=f(T_j); I_D=-15A; V_{GS}=-10V$



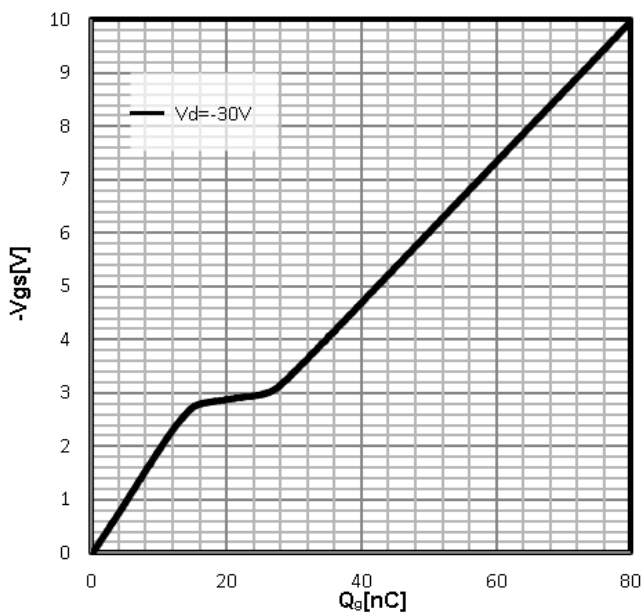
Gate Threshold Voltage
 $-V_{TH}=f(T_j); I_D=-250\mu A$



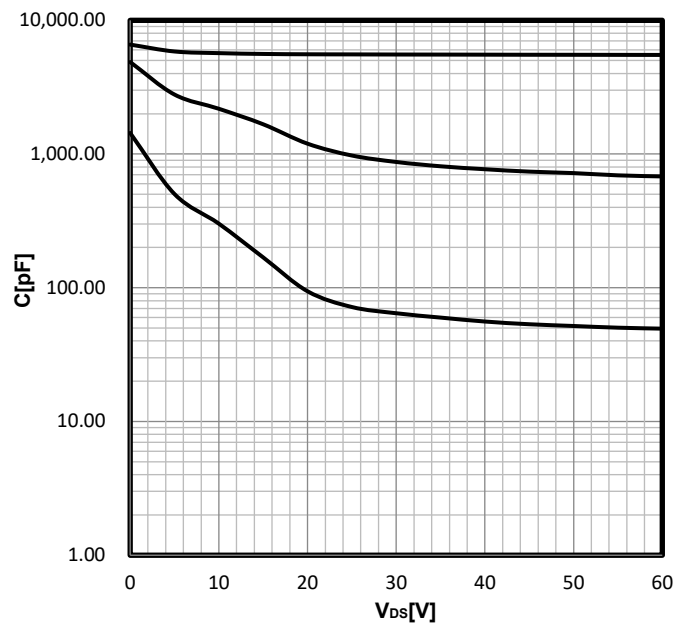
Drain-source breakdown voltage
 $V_{BR(DSS)}=f(T_j); I_D=-250\mu A$



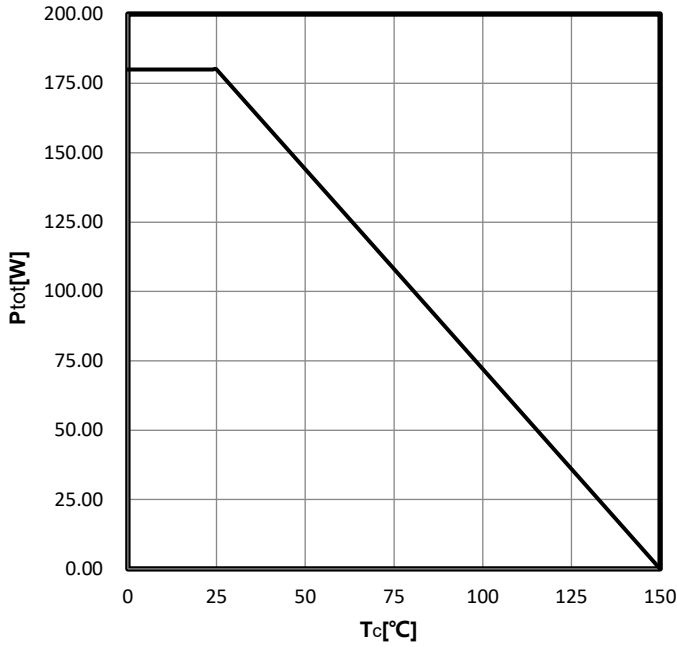
Typ. gate charge
 $V_{GS}=f(Q_{gate}); I_D=-15A$



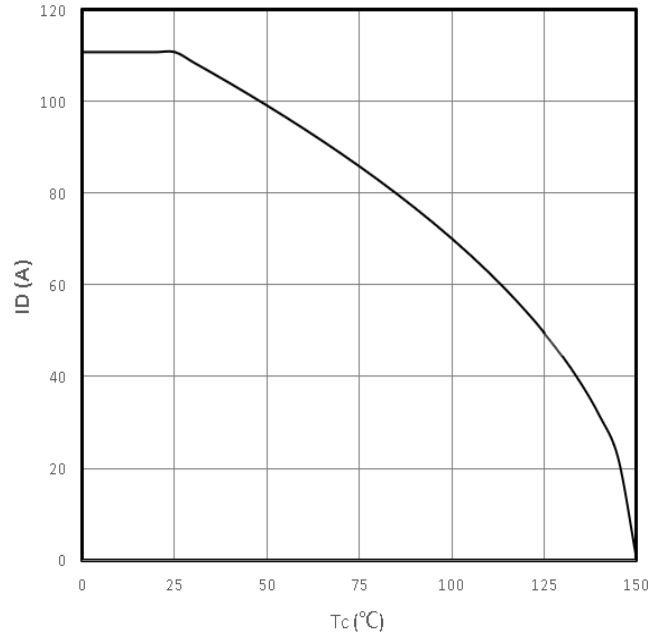
Typ. capacitances
 $C=f(V_{DS}); V_{GS}=0V; f=1MHz$



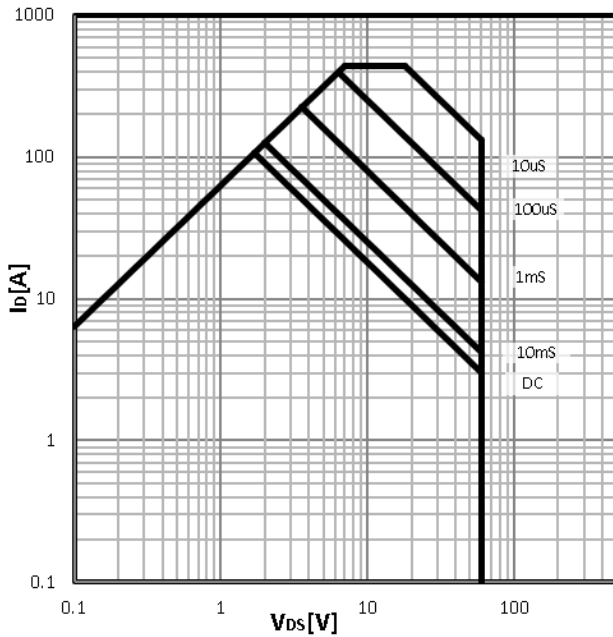
Power Dissipation
 $P_{tot}=f(T_C)$



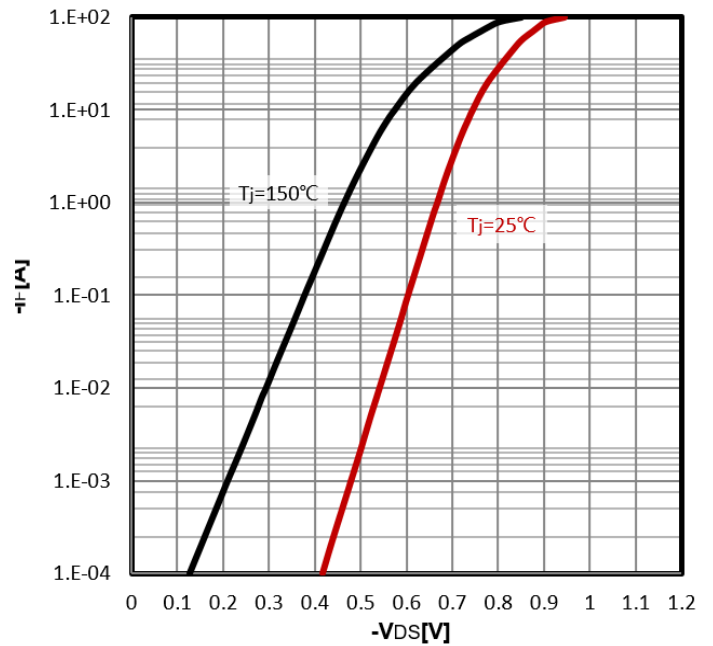
Maximum Drain Current
 $-I_D=f(T_C)$



Safe operating area
 $I_D=f(V_{DS})$

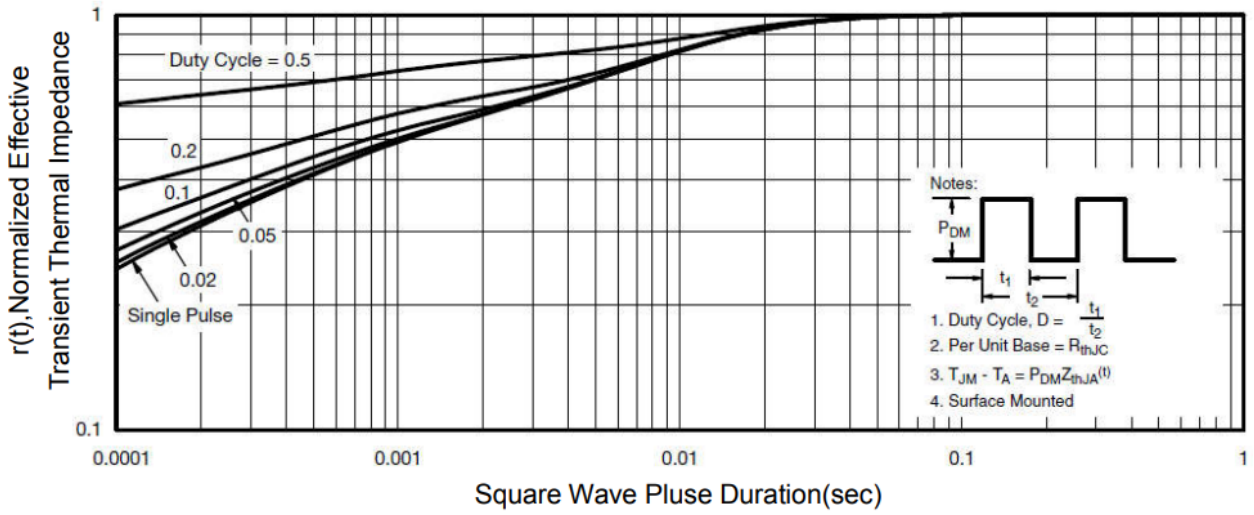


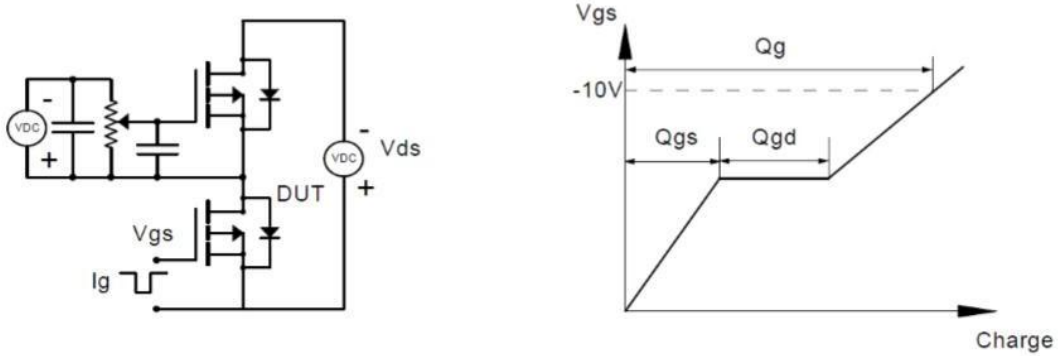
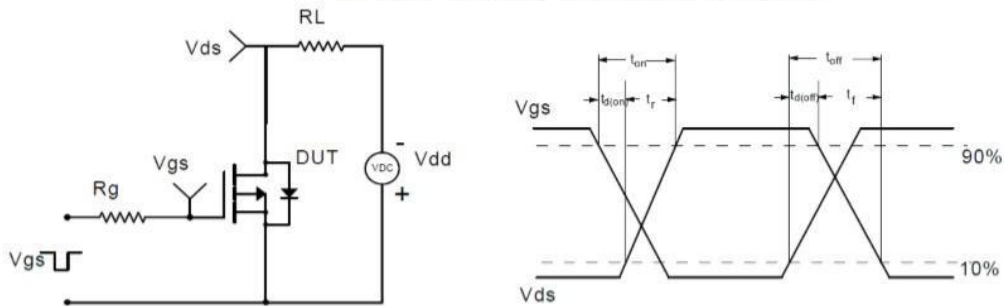
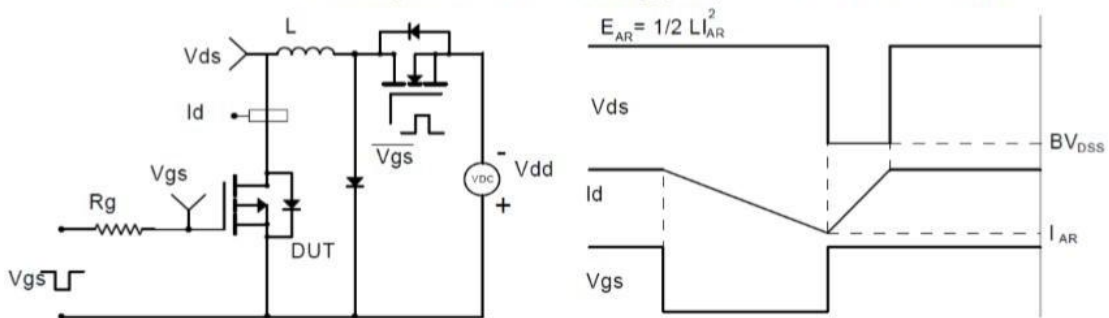
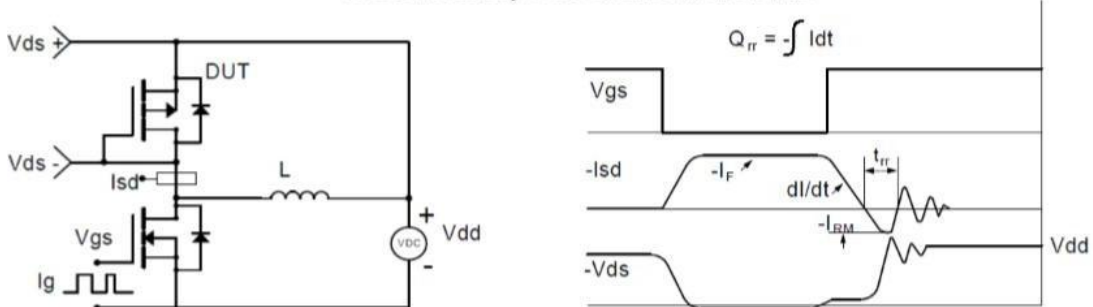
Body Diode Forward Voltage Variation
 $-I_F=f(-V_{DS})$

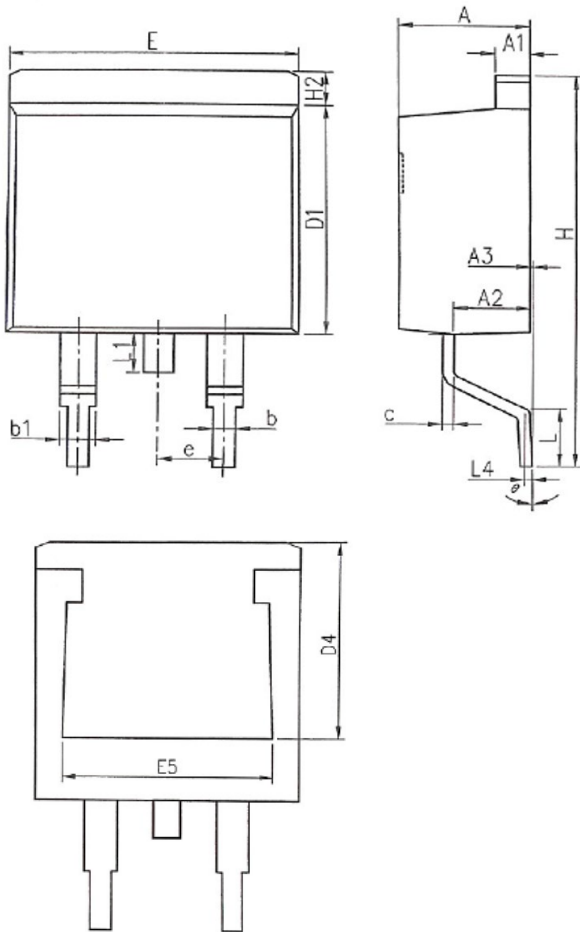


Max. transient thermal impedance

$$Z_{thJC} = f(t_p)$$



Test Circuit and Waveform:
Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms


Mechanical Dimensions for TO-263

COMMON DIMENSIONS

SYMBOL	MM	
	MIN	MAX
A	4.37	4.89
A1	1.17	1.42
A2	2.20	2.90
A3	0.00	0.25
b	0.70	0.96
b1	1.17	1.47
c	0.28	0.60
D1	8.45	9.30
D4	6.60	-
E	9.80	10.40
E5	7.06	-
e	2.54BSC	
H	14.70	15.70
H2	1.07	1.47
L	2.00	2.80
L1	-	1.75
L4	0.254BSC	
θ	0°	9°